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Date: February 28, 2006 File Number: 5649-1272

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Examiner Thomas L. Dickey, GAU 2826 U.S. Patent and Trademark Office

From: Mitchell S. Bigel

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Re: Deok-Hyung Lee et al., Integrated Circuit Field Effect Transistors
Including Channel-Containing Fin Having Regions of High and Low
Doping Concentration, Serial No. 10/801,614, filed March 16, 2004

Attached are the following documents responsive to the Advisory Action dated February 10, 2006:

1. Request for Continued Examination (RCE) Transmittal; and

2. Applicant Initiated Interview Request Form,

CERTIFICATION OF FACSIMILE TRANSMISSION UNDER 37 CFR § 1.8

I hereby certify that this correspondence is being facsimile transmitted to the U.S. Patent and Trademark Office via facsimile flumber 571-273-8300 on February 28, 2006.

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Date of Signature: February 28, 2006

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Attorney Docket No. 5649-1272 **PATENT** IN THE UNITED STATES PATENT AND TRADEMARK OFFICE RECEIVED CENTRAL FAX CENTER In re: Deok-Hyung Lee et al. Confirmation No.: 2903 Serial No.: 10/801,614 Examiner: Thomas L. Dickey FEB 2 8 2006 Filed: March 16, 2004 Group Art Unit: 2826 For: INTEGRATED CIRCUIT FIELD EFFECT TRANSISTORS INCLUDING CHANNEL-CONTAINING FIN HAVING REGIONS OF HIGH AND LOW DOPING CONCENTRATIONS February 28, 2006 Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 APPLICANT INITIATED INTERVIEW REQUEST FORM Sir: Tentative Participants: 1. Examiner Thomas L. Dickey 2. Mitchell S. Bigel Proposed Date of Interview: _____ Proposed Time: ____ At the Examiner's convenience. Type of Interview Requested: (1) [X] Telephonic (2) [] Personal (3) [] Video Conference Exhibit to be shown or demonstrated [] YES [X] NO If yes, provide brief description: ISSUES TO BE DISCUSSED Issues Claims/Prior Discussed Agreed Not Agreed (Rej., Obj., etc.) Fig. #s 1) Rejection [] [] Continuation Sheet Attached Brief Description of Arguments to be Presented: Discuss the scope and meaning of "confined laterally to beneath the channel region" and possible modification of this language per the Examiner's suggestion. An interview was conducted on the above-identified application on

Applicant/Applicant's Representative Signature

Examiner/SPE Signature